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PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10036625	FILING DATE 03/04/2002	CLASS 250	SUBCLASS 310	GAU 2818	EXAMINER Hughes
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\*\*APPLICANTS: Kochi Nobuc; Keiko Hirotami;

\*\*CONTINUING DATA VERIFIED:

None JH

\*\* FOREIGN APPLICATIONS VERIFIED:

JAPAN 2001-062686 03/06/2001 JH

JAPAN 2001-062687 03/06/2001

JAPAN 2001-062688 03/06/2001

PG-PUB <input type="checkbox"/>	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed 35 USC 119 conditions met		<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> yes <input checked="" type="checkbox"/> no	ATTORNEY DOCKET NO 035924-0103
Verified and Acknowledged Examiner's initials JH			
TITLE : Electron beam device and method for stereoscopic measurements U.S. DEPT. OF COMM./PAT. & TM-PTO-436 (Rev. 12-94)			

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G.
ISSUE FEE		DRAWING		
Amount Due	Date Paid	Sheets Drwg.	Figs. Drwg.	Print Fig.
TERMINAL DISCLAIMER		Primary Examiner		
		PREPARED FOR ISSUE		
		Application Examiner		
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